



Docket No.: 63979-033

PATENT

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of :  
Yoshihiko KANZAWA, et al. :  
Application No.: 10/674,523 : Group Art Unit: 2858  
Filed: October 01, 2003 : Examiner:  
For: METHOD FOR MEASURING SEMICONDUCTOR CONSTITUENT ELEMENT  
CONTENT AND METHOD FOR MANUFACTURING A SEMICONDUCTOR  
DEVICE (As amended)

**PRELIMINARY AMENDMENT**

Mail Stop Preliminary Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Prior to examination of the above-referenced application, please amend the application as follows:

IN THE SPECIFICATION:

Please amend the title as follows:

~~SPECIFICATION~~ METHOD FOR MEASURING SEMICONDUCTOR CONSTITUENT  
ELEMENT CONTENT AND METHOD FOR MANUFACTURING A SEMICONDUCTOR  
DEVICE